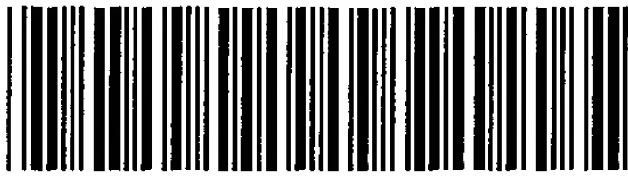


Search Notes

Application No.

09/499,765

Examiner

Patrick J. Nolan

Applicant(s)

HAYASHI ET AL.

Art Unit

1644

SEARCHED

Class	Subclass	Date	Examiner
424	185.1	9/17/03	PN
574	13		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
424	185.1	9/17/03	PN
574	13		
SEQ ID NO. 1			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
CONSIDERED PARENTS 09/076,938 08/736,434	9/17/03	PN
INVENTORS HAYASHI, SUBINO updated last and search		
SEQ ID NO. 1		